



*Minnowbrook  
Microelectronics*

*MB'26*

Dear Colleagues,

The world of high reliability microelectronic devices is rapidly advancing as new technical and material concepts are being developed to meet the demand for availability and reliability. This places a great burden on the supply houses, as the reliability of new technologies and materials needs to be proven. The reliability of hermetic device technology has been assured for decades via a multitude of testing scenarios - yet the new technologies and materials now create new concerns. Hermetic devices have gradually proven their place and now the application of non-hermetic devices in rugged environments is being advanced to allow use of devices only offered in a non-hermetic packaging. The new trends need to be proven for their respective applications. Hence, there is a need to openly discuss some of the underlying problems of the new technologies and materials, including process, failures and reliability testing related to non-hermetics. In addition, the efficacy and remaining issues in Test Methods 1014 (hermeticity testing) and 1018 (IGA testing) require continued attention as well as Test Method 5011 in addressing new materials.

Since Minnowbrook is based on informal open concepts in communication, it is a closed meeting i.e., there are no abstracts or written papers released to the general public. So - mark your calendar for attending MB'26 this November and check your email for registration information from the Coordinator of MB'26.

Danielle Moore, Chair

Steve Smalley, Co-Chair